

<b>Search Notes</b> 	<b>Application/Control No.</b> 09/710,487	<b>Applicant(s)/Patent under Reexamination</b> HENCH ET AL.
	<b>Examiner</b> Thien D. Tran	<b>Art Unit</b> 2616

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner